

Effect of Co/Sn Doping on the Thermal Stability of Magnetic Properties of Ba-Ferrite

Thin Films

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Abstract—BaFe_{12-2x}Co_xSn_xO₁₉ (where $x=0 \sim 1.03$) thin films were made by rf magnetron sputtering in Ar-O₂ mixed atmosphere. These films were then post-annealed in air between 850°C and 1000°C for 10 minutes, in order to get M-type phase. The contents of Co/Sn on the magnetic properties and thermal stability of the magnetic properties of the films were discussed.

I. INTRODUCTION

Recently, there has been interested in using thin film BaM for high density magnetic recording media, because it possess not only excellent magnetic properties but also has good mechanical and chemical stability. Sputtered Ba-ferrite thin films under normal conditions are amorphous structure in nature and they are nonmagnetic [1]. Hence, crystalline BaM thin films have to be obtained by either applying in-situ substrate heating during deposition [2] or through a post-deposition annealing treatment [3].

Many investigators [4-6] indicate that Co/Ti doped BaM particles could reduce grain size of the particles. However, their temperature coefficient of coercivity dH_c/dT is about $+3 \sim +4 \text{ Oe}/^\circ\text{C}$ [7]. Kubo et al. [7] have substituted various third elements into the Ba-ferrite particles. They found that Sn is the most effective element in reducing dH_c/dT of the particles. Li and Sinclair [8] found that temperature coefficient of coercivity dH_c/dT of the Ti/Zn doped BaM thin film is about $+0.5 \text{ Oe}/^\circ\text{C}$ for perpendicular coercivity and $-3 \text{ Oe}/^\circ\text{C}$ for in-plane coercivity.

In this report, we investigate the effect of Co/Sn doping on the thermal stability of the magnetic properties of the BaM films. The effects of Co/Sn contents and annealing temperature on the perpendicular and in-plane magnetic properties of the Co/Sn doped BaM thin films were also examined.

II. EXPERIMENT

BaFe_{12-2x}Co_xSn_xO₁₉ (where $x=0 \sim 1.03$) thin films were made by rf magnetron sputtering system in the Ar - O₂ mixed

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atmosphere, then post-annealed in air between 850°C and 1000°C for 10 minutes. Co/Sn doped BaM targets were used in this experiment. All of the films were deposited onto a room-temperature fused silica glass substrate. The base pressure in the system was 1×10^{-5} Torr, and after the high purity Ar-O₂ mixed gas (Ar : O₂ = 9 : 1) was introduced, sputtering pressure was 5×10^{-3} Torr. Thickness of the films was 100 nm.

The structure and phase types of the films were determined by using x-ray diffractometer (XRD). Magnetic properties of the films were measured with vibrating sample magnetometer (VSM) at room temperature with maximum applied field of 12 kOe. Composition and homogeneity of the films were determined by energy disperse x-ray spectrometer (EDS). Thickness of the films was measured by a α -step.

III. RESULTS AND DISCUSSION

Figure 1 shows the coercivity H_c and saturation magnetization M_s of the BaFe_{12-2x}Co_xSn_xO₁₉ thin films as a function of Co/Sn content x . These films were post-annealed at 950°C for 10 minutes in air. It can be seen that both the out-plane coercivity $H_{c\perp}$ and in-plane coercivity $H_{c\parallel}$ decrease dramatically with increasing x while the saturation magnetization M_s decreases slowly with increasing x . For pure BaM film, its $H_{c\perp}$ is about 3200 Oe, $H_{c\parallel}$ is about 2200 Oe, and M_s is about 320 emu/cm³. As x is increased to 0.83, they decrease to about 1100 Oe, 850 Oe, and 240 emu/cc, respectively for $x=0.83$. The out-plane coercivity always higher than that of in-plane for the same x . The increasing of Co/Sn content x will suppress the out-plane coercivity more than that of the in-plane coercivity. Hence, we can get nearly magnetic isotropy BaM thin films (i.e., $H_{c\perp} \cong H_{c\parallel}$) by doping proper amount of Co/Sn.

The magnetic moment of Ba-ferrite unit cell is coming from the resultant moment of Fe³⁺ ions at spin-up (12k,2b) and spin-down (4f₂) sites [9]. The decrease of M_s value with increasing x is due to that the substitution of these magnetic Fe³⁺ ions with nonmagnetic Sn⁴⁺ ions. On the other hand, the Fe³⁺ ions at 12k and 2b sub-lattices are major contributors to the overall uniaxial anisotropy of BaM ferrite [10]. The substitution of Fe³⁺ ions with Co²⁺ and Sn⁴⁺ ions at 12k and 2b

sites will destroy the exchange interaction between adjacent 12k and 2b sites and reduce the coercivity of BaM.

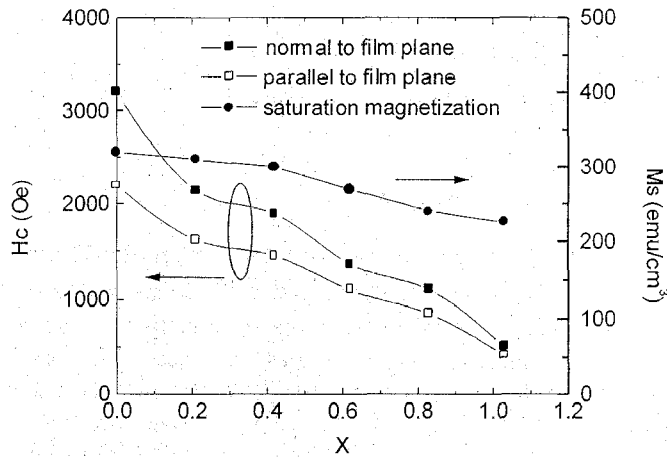


Fig. 1. Coercivities and the saturation magnetization M_s as function of Co/Sn-doping x for the $\text{BaFe}_{12-2x}\text{Co}_x\text{Sn}_x\text{O}_{19}$ thin films. These films were post-annealed at 950°C for 10 minutes in air.

Figure 2 shows the variation of M_s with temperature between 20°C and 100°C for various $\text{BaFe}_{12-2x}\text{Co}_x\text{Sn}_x\text{O}_{19}$ thin films. It is obviously that the value of M_s decreases with increasing temperature. In figure 2, we can see that the slope of M_s vs. T curve is decreased with increasing x . This is due to that the variation of M_s with temperature is dominated by the interactions of 12k-2a ions and 12k-12k ions for small x ($x=0\sim 0.42$). But, it is dominated by the perturbing effect of 12k-2b interaction for larger x ($x=0.62\sim 1.02$) [11].

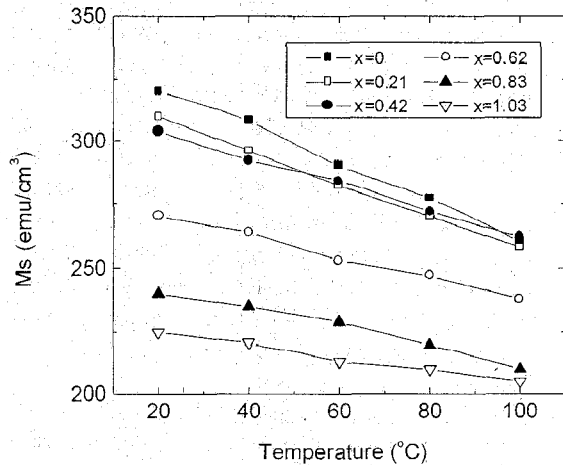


Fig. 2. The M_s value of $\text{BaFe}_{12-2x}\text{Co}_x\text{Sn}_x\text{O}_{19}$ thin films as function of temperature between 20°C and 100°C .

The temperature coefficient of coercivity, defined by dH_c/dT , was determined as $dH_c/dT = [H_c(100^\circ\text{C}) - H_c(20^\circ\text{C})] / 80^\circ\text{C}$. Where $H_c(100^\circ\text{C})$ and $H_c(20^\circ\text{C})$ are the

coercivities at 100°C and 20°C , respectively. The values of dH_c/dT as a function of x for the $\text{BaFe}_{12-2x}\text{Co}_x\text{Sn}_x\text{O}_{19}$ thin films are plotted in figure 3. These curves indicate that both in-plane and out-plane coercivities are increased with increasing temperature for $x < 0.62$, and decreased with increasing temperature for $x > 0.62$. The dashed line indicates that the coercivity is not affected by the temperature. The out-plane dH_c/dT of the film is decreased from $+4.2$ to -1.3 $\text{Oe}/^\circ\text{C}$, and out-plane dH_c/dT decreases from $+4.8$ to -1.1 , as x increase from 0 to 1.03. For $x=0.62$, the values of out-plane and in-plane dH_c/dT are 0.1 $\text{Oe}/^\circ\text{C}$ and 0.2 $\text{Oe}/^\circ\text{C}$, respectively.

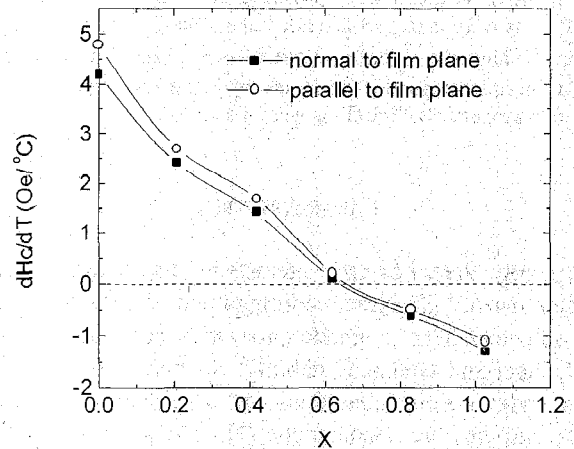


Fig. 3. The temperature coefficient of coercivity dH_c/dT as function of x for various $\text{BaFe}_{12-2x}\text{Co}_x\text{Sn}_x\text{O}_{19}$ thin films.

Figure 4 shows X-ray diffraction patterns of the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ films which annealed at temperatures between 850°C and 1000°C for 10 minutes in order to avoid grain growth. It reveals that completely M-type Ba-ferrite can be obtained when the annealing temperature T_A is higher than 950°C . As T_A is lower than 900°C , we can see that there has nonmagnetic $\alpha\text{-Fe}_2\text{O}_3$ phase appeared.

Figure 5 shows the variations of H_c and M_s of the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin film with annealing temperature between 850°C and 1000°C . M_s is increased with annealing temperature T_A and the increase of M_s becomes slowly as $T_A > 950^\circ\text{C}$. H_c is also increased with T_A as T_A is lower than 950°C , but it decreases when T_A is higher than 950°C . When $T_A < 950^\circ\text{C}$, the increase of M_s and H_c with T_A is due to the decrease of nonmagnetic amorphous phase and $\alpha\text{-Fe}_2\text{O}_3$ phase as shown in Fig.4. As T_A is higher than 950°C , the decrease of H_c is due to rapid grain growth of the film, as shown in figure 6. Figure 6 shows the variation of average grain size of the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin film with T_A . It can be seen that the average grain size increases slowly from 12nm to 20nm when T_A is increased from 850°C to 950°C , and it increases rapidly as $T_A > 950^\circ\text{C}$. The average grain size was calculated from scherrer formula [12] with half-maximum peak width of the main peak (008) in figure 4.

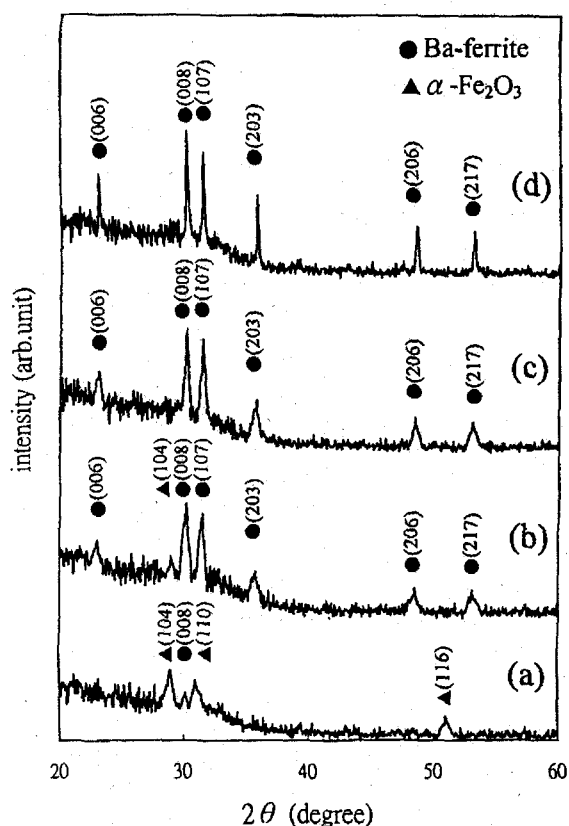


Fig. 4. X-ray diffraction patterns of the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin films which are annealed at various temperatures: (a) 850°C; (b) 900°C; (c) 950°C; (d) 1000°C.

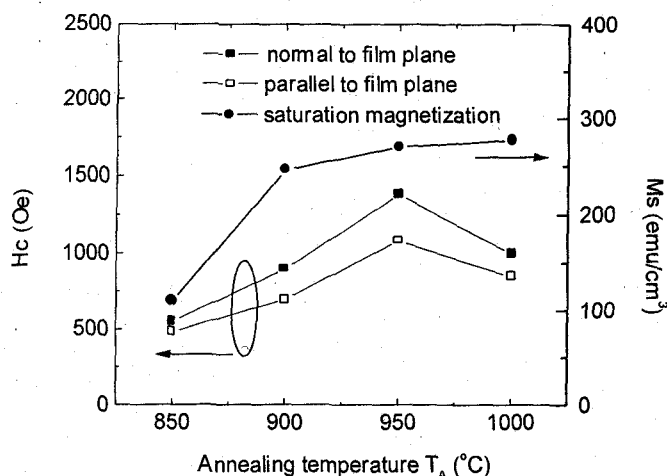


Fig. 5. Coercivities and the saturation magnetization as function of annealing temperature for the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin films. These films were post-annealed for 10 minutes in air.

IV. CONCLUSION

The Co/Sn doped barium ferrite (BaM) thin films had been prepared by using rf magnetron sputtering. M_s , $H_{c\perp}$, and $H_{c\parallel}$ of the film was decreased with increasing Co/Sn concentration. For the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin film, both in-plane and out-plane coercivities almost keep constant with

temperature between 20 °C and 100 °C. Its out-plane coercivity is about 1400 Oe and in-plane coercivity is about 1100 Oe. The saturation magnetization M_s is about 270 emu/cm^3 and the average grain size is about 20 nm. It reveals that this $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin film has excellent magnetic thermal stability.

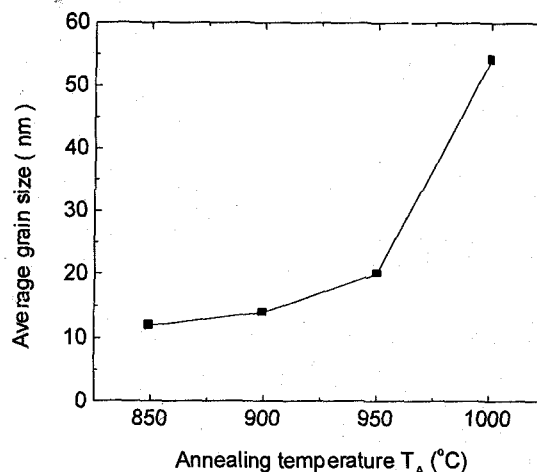


Fig. 6. Average grain size as function of annealing temperature for the $\text{BaFe}_{10.76}\text{Co}_{0.62}\text{Sn}_{0.62}\text{O}_{19}$ thin films. These films were post-annealed at 850°C \sim 1000°C for 10 minutes in air.

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